Application/Control No. Applicant(s)/Patent Under Reexamination 10/044,271 CHEN ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Stephen J. Stein 1775 **U.S. PATENT DOCUMENTS Document Number** Date Classification Country Code-Number-Kind Code Name MM-YYYY Α US-2003/0123167 A1 07-2003 Kolberg et al. 359/885 US-В С US-D US-Ε US-F US-G US-Н US-US-1 US-J US-Κ L US-US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Country Country Code-Number-Kind Code Name Classification MM-YYYY Ν 0 Ρ Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

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